APPROVAL SHEET

 Customer
 Name
 :

 Customer
 P/N
 :

 Frequency
 : 32.000000
 MHz

 Aker Approved P/N:
 CXAN-032000-A-AL-07

 Aker MPN
 : CXAN-032000-A-AL-07

 Rev.
 : 1

 ISSUE DATE
 : Feb.5.2024

| APPROVED | CHECKED | PREPARED |
|----------------|---------|----------|
| Lei | | PTY |
| APPROVED BY CU | STOMER | |
| | | |

AKER TECHNOLOGY CO., LTD.

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Web: www.aker.com.tw MSL:Level 1

RoHS compliance



| Aker Approved P/N | : | CXAN-032000-A-AL-07 | | | |
|-------------------|---|---------------------|---------------|--|--|
| APPROVED | : | Xtal | SHEET: 1 of 9 | | |
| PREPARED | : | piy | REV . : 1 | | |

| Rev. | Date | Reviser | Revise contents |
|------|----------|---------|------------------|
| | | | |
| 1 | 2024/2/5 | piy | Initial Released |
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SMD CRYSTAL SPECIFICATION

1. ELECTRICAL CHARACTERISTICS

■ Standard atmospheric conditions

Unless otherwise specified, the standard range of atmospheric conditions for making measurement and tests are as follow:

Ambient temperature: 25±5 ℃

Relative humidity : 40%~70%

If there is any doubt about the results, measurement shall be made within the following limits:

Ambient temperature : 25±3 ℃

Relative humidity : 40%~70%

■ AKER Model: CXA-211

Oscillation Mode : Fundamental

■ Cutting Mode : AT CUT

■ Measurement Equipment : 250B(Measured FL)

■ Insulation Resistance : More than 500M ohms at DC 100V

| | | Electrical Spec | | | | |
|------------------------------|--------|-----------------|---------|------|------------------------|-------------------------------------|
| Parameters | Symbol | Min. | Тур. | Max. | Units. | Notes |
| Nominal Frequency | FL | 32 | 2.00000 | 0 | MHz | |
| Frequency Tolerance | | | ±20 | | ppm | at 25° C $\pm 3^{\circ}$ C |
| Frequency Stability | | ±20 | | | ppm | Operating Temp (Refer 25°℃) |
| Load Capacitance | CL | | 8 | | pF | |
| Aging | | | ±3 | | ppm | First Year at 25°C |
| Operating Temperature | | -40 | ~ | 85 | $^{\circ}\!\mathbb{C}$ | |
| Storage Temperature Range | | -55 | ~ | 125 | $^{\circ}\!\mathbb{C}$ | |
| Drive Level | DL | | | 100 | uW | |
| Equivalent Series Resistance | ESR | | | 80 | Ω | @Series |
| Shunt Capacitance | C0 | | | 3 | pF | |

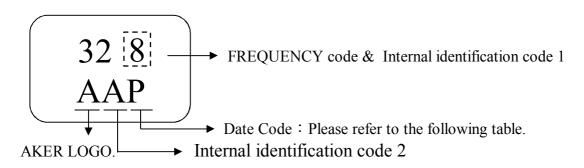
^{*}Please kindly be noted that AKER DO NOT guarantee parts quality which involves human security application.*



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| APPROVED : | Xtal | SHEET: 3 of 9 |
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(Unit:mm)

2. MARKING:

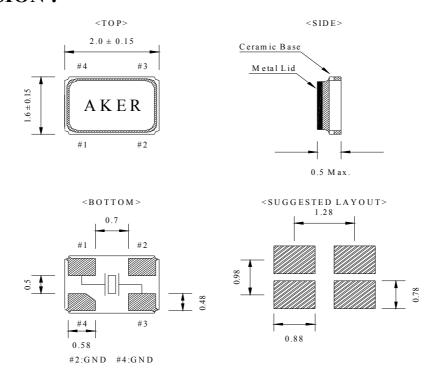


Date Code Table

| | Month Year | | 1 | 2 | 3 | 4 | 5 | 6 | 7 | 8 | 9 | 10 | 11 | 12 |
|------|---------------|--------|---|---|---|---|---|---|---|---|---|----|----|----|
| 2019 | 2023 | (4N+3) | Α | В | С | D | Е | F | G | Н | J | K | L | М |
| 2020 | 2024 | (4N+0) | N | Р | Q | R | S | Т | U | V | W | Х | Υ | Z |
| 2021 | 2025 | (4N+1) | а | b | С | d | е | f | g | h | j | k | | m |
| 2022 | 2026 | (4N+2) | n | р | q | r | S | t | u | ٧ | W | Х | У | Z |

A cycle every four years

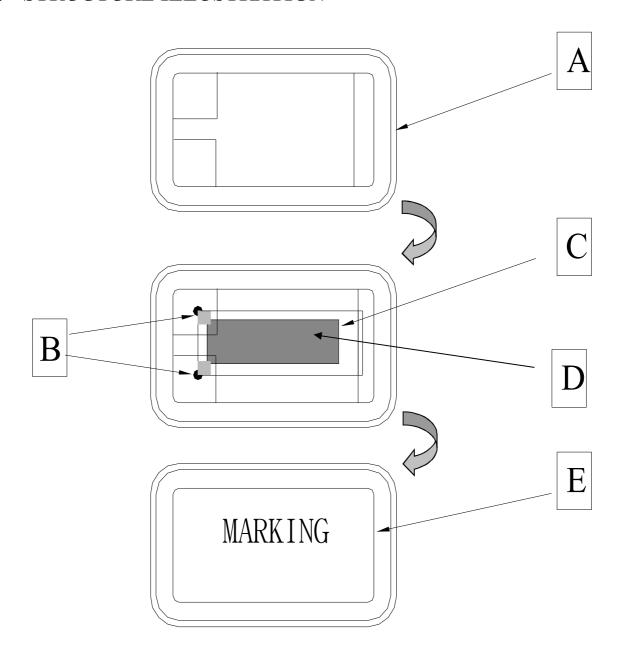
3. DIMENSION:





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4. STRUCTURE ILLUSTRATION



| | COMPONETS | MATERIALS | | MPONENTS | MATERIALS |
|---|----------------------|--------------------------------|---|-----------|-------------|
| Α | Base(Package) | Ceramic(Al2O3)+Kovar(Fe/Co/Ni) | D | Electrode | Noble metal |
| В | Conducitive adhesive | Ag / Silicon resin | Е | Lid | Fe/Co/Ni |
| С | Crystal blank | SiO2 | | | |

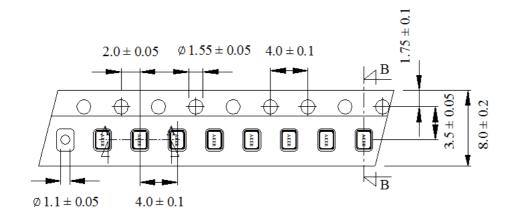


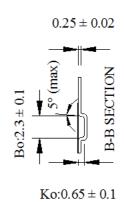
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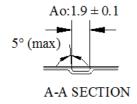
5. PACKING:

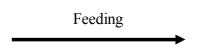
TAPE SPECIFICATION

(Unit:mm)



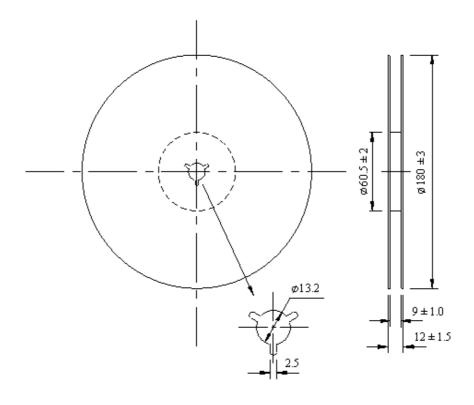






OUTLINE DIMENSION

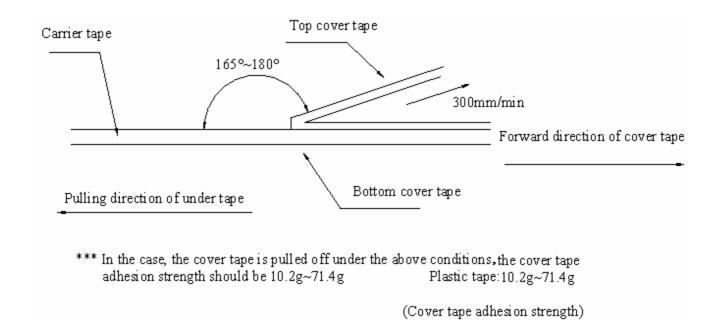
(Unit:mm)



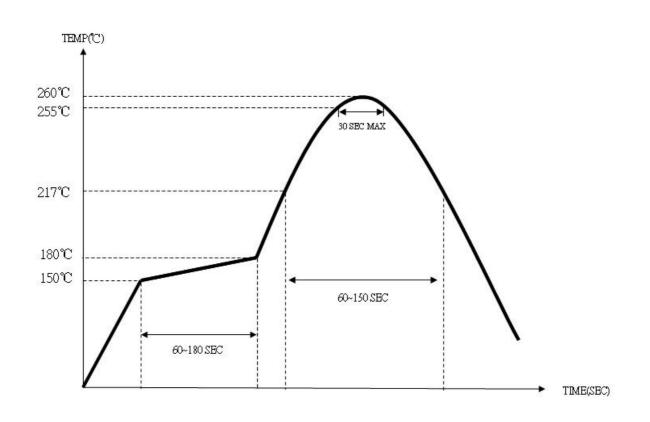


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6. COVER TAPE ADHESION STRENGTH:



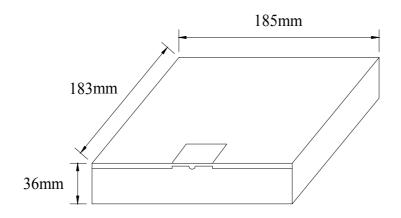
7. SOLDERING REFLOW PROFILE





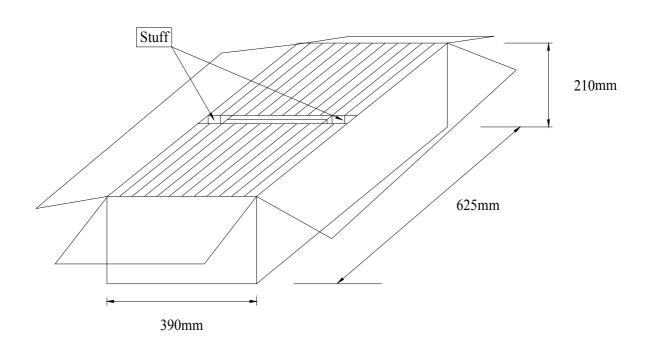
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8. PACKING:



BOX = 3000 PCS / REEL(MAX)





SMD product packs 32 BOX=The outside box packs (3000 PCS *32 BOX = 96000 PCS)(MAX)



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9. MECHANICAL PERFORMANCE

| TEST ITEMS | TEST METHODS AND TEST CONDITION | PERFORMANCE |
|--------------------|----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|----------------------------------------------------------|
| 9.1 Drop Test | The specimen is measured for its frequency and resistance before the test. It is then dropped from a hight of 75 cm or more as a free fall object onto a hard wooden plate of 30mm or more in thickness. (in accordance with JIS-C0044) | |
| 9.2 Vibration Test | The specimen is measured for its frequency and resistance before the test. Most them into X,Y and Z axes, respectively, for the vibration test. Vibration condition: Frequency range; 20 ~ 2000HZ Peak to peak amplitude: 1.52 mm Peak acceleration: 20G Sweep time: 20 minute / axis Pendicular total test time: 4 hours | To satisfy the electrical performance. |
| 9.3 Resistance to | (in accordance with MIL-STD-883F : 2007.3) The specimen is measured for its frequency and | _ |
| Soldering Test | resistance before the test. Place the specimen on the belt of the converynace and let it pass through the reflow with the presetted temperature condition. After passing twice the reflow place, the specimen under the referee condition for -~2 hours and then | |
| | measure its electrical performance. Temperature Condition of IR Simulation: The temperature range of the preheated section is setted at 150° 180° C for 60° 120 sec. For the next section the temperature range is setted at 217° 260°C for 45° 90 sec. and within this time range the specimen should be able to sustain at the peak temperature, 260° 10 sec long. | |
| 9.4 Fine Leak | (in accordance with JESD22-B106-B) | |
| Test | Place the specimen in a pressurized container and pressurize it with the detection gas (mixed gas consisting of 95% or more helium) for at least 2 hours. Complete the measurement of the concentration of helium within 30 min after taking it out from the pressurized container. | Less than 1.0 * 10 ⁻⁸ atm .c.c. / sec, Helium |
| | (in accordance with MIL-STD-883F: 1014.11) | |
| | The referee condition. Temperature $25 \pm 2 ^{\circ}\mathbb{C}$ Humidity $44 ^{\circ} 55 ^{\circ}\mathbb{W}$ Pressure $86 ^{\circ} 106 \text{ kPa}$ | |
| | (in accordance with MIL-STD-883E: 1014. 9) | |



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10. CLIMATIC RESISTANCE

| TEST ITEMS | TEST METHODS AND TEST CONDITION | PERFORMANCE |
|--------------------------------------|-----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|-----------------------------------------|
| 10.1 Low Temp Exposure Test | The specimen is measured for its frequency and resistance before the test . Place the specimen in the chamber and kept it at the temperature of - $40 \pm 3^{\circ}$ C for 168 ± 6 hours . Take the specimen out of the chamber and measure itselectrical performance after leaving 1 $^{\sim}$ 2 hours under the referee condition. (in accordance with JIS-C0020) | |
| 10.2 Aging Test | The specimen is measured for its frequency and resistance before the test. Place the specimen in the testing chamber and keep it at the temperature of $+125 \pm 3^{\circ}\mathbb{C}$ for 720 ± 48 hours. And then take the specimen out of the chamber and measure its electrical performance after leaving for 1° 2 hours under the referee condition. (in accordance with JIS-C0021) | To satisfy the electrical performance . |
| 10.3 High Temperature & High Humidty | The specimen is measured for its frequency and resistance before the test . Place the specimen in the testing chamber and kept it at the temperature of $+85 \pm 5$ °C and humidity of 85 ± 5 % for 168 ± 6 hours and then take the specimen out and measure its electrical performance after leaving for 1^{\sim} 2 hours under the referee condition. (in accordance with MIL-STD-883F: 1004.7) | |
| 10.4 Temperature Cycle Test | The specimen is measured for its frequency and resistance before the test . Subject the specimen to the 100 cycles of temperature ranges stated below . High temp . + $125 \pm 3 ^{\circ}\text{C} (15 \pm 3 \text{min})$. Low temp55 ±3 $^{\circ}\text{C} (15 \pm 3 \text{min})$. Measure its electrical performance after leaving it for 1 $^{\circ}$ 2 hours under the referee condition . (in accordance with MIL-STD-883F: 1010.8) | |

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